

Description

The VSM5P10 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. It is ESD protested.

General Features

V_{DS} =-100V,I_D =-5A

 $R_{DS(ON)}$ <100m Ω @ V_{GS} =-10V (Typ:85m Ω)

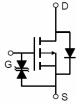
 $R_{DS(ON)}$ <120m Ω @ V_{GS} =-10V (Typ:95m Ω)

- Super high dense cell design
- Advanced trench process technology
- Reliable and rugged
- High density celldesign for ultra low on-resistance

Application

- Power switch
- DC/DC converters





SOP-8

Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM5P10-S8	VSM5P10	SOP-8	Ø330mm	12mm	4000 units

Absolute Maximum Ratings (T_c=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	-100	V	
Gate-Source Voltage	Vgs	±20	V	
Drain Current-Continuous	I _D	-5	А	
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	-3.5	Α	
Pulsed Drain Current	I _{DM}	-30	А	
Maximum Power Dissipation	P _D	3.1	W	
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 150	$^{\circ}$ C	

Thermal Characteristic

Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{\theta JA}$	40	°C/W
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Electrical Characteristics (Tc=25℃unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						





Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-100	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-100V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±10	μA
On Characteristics (Note 3)			'			1
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =-250μA	-1	-1.9	-3	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D =-5A	-	85	100	mΩ
		V _{GS} =-4.5V, I _D =-5A		95	120	
Forward Transconductance	g FS	V _{DS} =-5V,I _D =-5A	5	-	-	S
Dynamic Characteristics (Note4)	•		•			•
Input Capacitance	C _{lss}	V _{DS} =-50V,V _{GS} =0V,	-	3810	-	PF
Output Capacitance	C _{oss}		-	129	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	125	-	PF
Switching Characteristics (Note 4)	•		•			•
Turn-on Delay Time	t _{d(on)}	V_{DD} =-50V, I_{D} =-5A V_{GS} =-10V, R_{GEN} =9 Ω	-	16	-	nS
Turn-on Rise Time	t _r		-	73	-	nS
Turn-Off Delay Time	t _{d(off)}		-	34	-	nS
Turn-Off Fall Time	t _f		-	57	-	nS
Total Gate Charge	Qg	V _{DS} =-50V,I _D =-5A,	-	70	-	nC
Gate-Source Charge	Q _{gs}		-	12.5	-	nC
Gate-Drain Charge	Q _{gd}	V _{GS} =-10V	-	15.5	-	nC
Drain-Source Diode Characteristics	·	•	•			
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =-5A	-	-	-1.2	V
Diode Forward Current (Note 2)	Is	-	-	-	-5	Α
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F =-5A	-	88.3	-	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/μs ^(Note3)	-	65.9	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

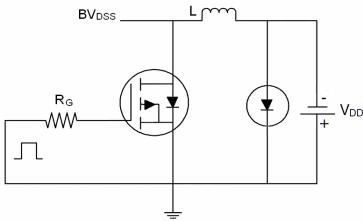
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition: Tj=25 $^{\circ}\text{C}$,VDD=-50V,VG=-10V,L=0.5mH,Rg=25 Ω

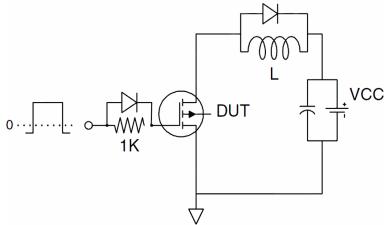


Test Circuit

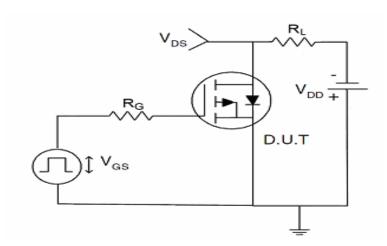
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics (Curves)

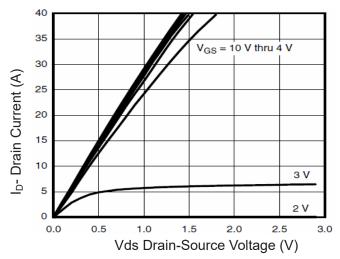


Figure 1 Output Characteristics

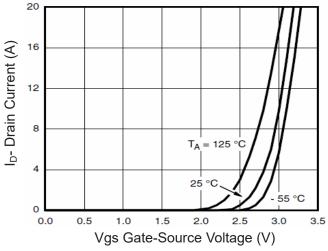


Figure 2 Transfer Characteristics

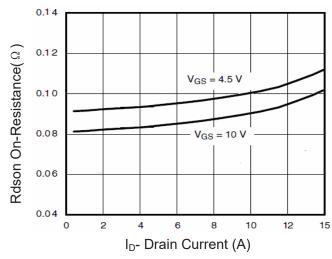


Figure 3 Rdson- Drain Current

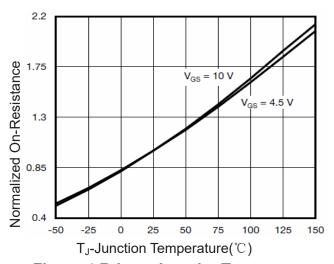


Figure 4 Rdson-JunctionTemperature

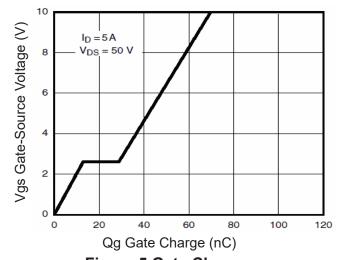


Figure 5 Gate Charge

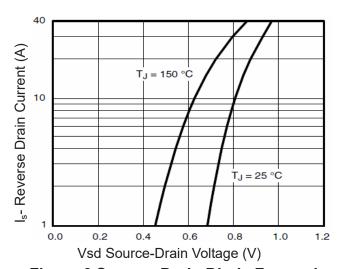
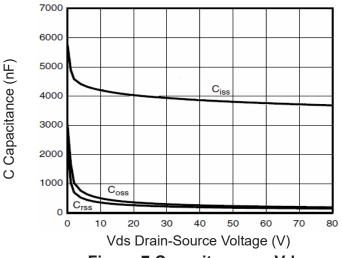


Figure 6 Source- Drain Diode Forward

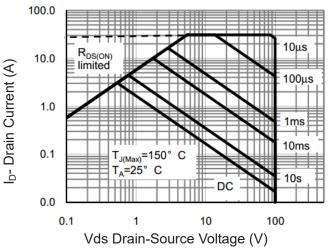




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Figure 7 Capacitance vs Vds

Figure 9 Drain Current vs Case Temperature



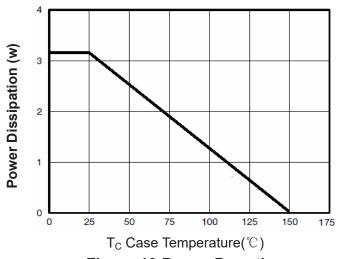


Figure 8 Safe Operation Area

Figure 10 Power De-rating

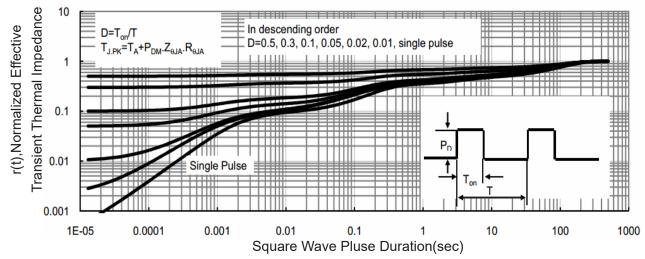


Figure 11 Normalized Maximum Transient Thermal Impedance